## In the Claims:

Claims 6, 11, 14, 17 and 20 have been amended as follows:

2 V 3

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6. (Amended) A method according to claim 5 wherein the elements are configured in an array of rows and columns, and including combining the resultant data for at least a part of an individual one of the rows or columns, and comparing the combined data with a threshold to provide an indication of a malfunction in the device.

11. (Amended) A method according to claim 1 wherein the display device is mounted in an electronic apparatus with a back light operable to illuminate the display device, including capturing the data corresponding to the first and second images with the back light in use.



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14. (Amended) Apparatus according to claim 13 wherein the test pattern generator is configured to energise and de-energise the elements individually to produce the data corresponding to the first and second images.



17. (Amended) Apparatus according to claim 12 wherein the processor is configured to compare the image data for the first and second images to provide resultant data corresponding to the functionality of the elements individually.